Se	arch	Notes	;

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/776,347	TANAKA ET AL.	
Examiner	Art Unit	_
Yonel Beaulieu	3661	

	SEARCHED			
Class	Subclass	Date	Examiner	
701	41	1/15/2006	YB	
	42			
180	443	1/20/2006	YB	
	444			
74	7D	1/20/2006	YB	
	10.85			
	425			
	724			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
WEST + Inventor's Name Search	1/15/2006	ΥB
WEST	1/20/2006	ΥB
Consulted w/Ex. Boehler (180)	1/20/2006	YB